

Search Notes

Application/Control No.

10/709,319

Examiner

Charles R. Kasenge

Applicant(s)/Patent under
Reexamination

CONRAD ET AL.

Art Unit

2125

SEARCHED

Class	Subclass	Date	Examiner
700	95	11/24/2004	CK
	100		
	103		
	108		
	109		
	110		
	115		
	116		
	117		
	121		
438	5		
	7		
	8		
	9, 14		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
700	108	7/1/2005	CK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search; search terms: semiconductor, tool, sampling, metrology	11/24/2004	CK